

RELIABILITY DATA LTC1325 8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SOIC/SOT/MSOP	104 104	9413	9413	104.06 104.06	0 0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	201	9447	9835	4.91	0
SOIC/SOT/MSOP	400	9447	9907	31.27	0
	601			36.18	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	50	9447	9447	1.20	0
SOIC/SOT/MSOP	50	9447	9447	5.00	0
	100			6.20	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	49	9447	9447	4.90	0
	49			4.90	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Not Enough Data to Predict Failure Rate

(3) Refer to Rel Data Pack for Generic Product Family Data

Note: 1 FIT = 1 Failure in One Billion Hours.